CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board
500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

SMT Corporation
14 High Bridge Road
Sandy Hook, CT 06482

has been assessed by ANAB
and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the fields of

TESTING

Refer to the accompanying Scope of Accreditation for information regarding the types of calibrations and/or tests to which this accreditation applies.

AT-1733
Certificate Number

ANAB Approval

Certificate Valid:03/06/2018-10/22/2018
Version No. 003 Issued: 10/22/2018

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

ANSI-ASQ National Accreditation Board

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

SMT Corporation

14 High Bridge Road, Sandy Hook, CT 06482
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TESTING

Valid to: **October 22, 2018** Certificate Number: **AT-1733**

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Radiographic Examination / Inspection	Internal Procedure: W750-15 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Glenbrook Jewel-box 90T
Scanning Electron Microscopy (SEM) Examination / Inspection	Internal Procedure: W750-12 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Tescan
Visual Inspection	Internal Procedure: W750-18 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Dinocapture 2.0 To 230x

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Resistance to Solvents (RTS) / Scrape Test	Internal Procedure: W750-11 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Removal of Residue
Packaging Configuration and Dimensions	Internal Procedure: W750-19 MIL-STD-883 Method 2016 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Calipers Device to print Package Dimensions

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Dynasolve	Internal Procedure: W750-09 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Removal of Residue
Decapsulation and Die Verification	Internal Procedure: W750-21 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Nisene Jet-Etch Acid Decapsulator

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Capacitance Measurement	MIL-STD-202G METHOD 305A Internal Procedure: W750-03	Electrical, Electronic and Electromechanical (EEE) Components	LCR Meter – Quadtech 7600B
Contact Resistance	MIL-STD-202 Method 307 Internal Procedure: W750-02	Electrical, Electronic and Electromechanical (EEE) Components	Multimeter
Forward voltage drop	MIL-STD-750 METHOD 4011 Internal procedure: W750-4011.4	Diodes	PXI-4130 Source-Measure Unit PXI-4072 DMM, PXI-5122 Digitizer (Oscilloscope) PXIe-6556 Digital Waveform Generator
Reverse Current Leakage	MIL-STD-750 METHOD 4016 Internal procedure: W750-4016.4	Diodes	PXI-4130 Source-Measure Unit
Regulator (breakdown) Voltage	MIL-STD-750 METHOD 4022 Internal procedure: W750-4022	Zener Diodes	PXI-4130 Source-Measure Unit PXI-4072 DMM
Propagation Delay	MIL-STD-883 METHOD 3003 Internal procedure: W883-3003	Microcircuits	PXI-4110 Power Supply PXI-6556 Digital Waveform Generator LeCroy WavePro 7300A 3GHz Oscilloscope

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Power Supply Current	MIL-STD-883 METHOD 3005 Internal procedure: W883-3005	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
High Level Output Voltage	MIL-STD-883 METHOD 3006 Internal procedure: W883-3006	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Low Level Output Voltage	MIL-STD-883 METHOD 3007 Internal procedure: W883-3007	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Low Level Input Current	MIL-STD-883 METHOD 3009 Internal procedure: W883-3009	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
High Level Input current	MIL-STD-883 METHOD 3010 Internal procedure: W883-3010	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Output Short Circuit Current	MIL-STD-883 METHOD 3011 Internal procedure: W883-3011	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Functional Testing	MIL-STD-883 METHOD 3014 Internal procedure: W883-3014	Microcircuits	PXI-4110 Power Supply PXI-6556 Digital Waveform Generator
Input Clamp Voltage	MIL-STD-883 METHOD 3022 Internal procedure: W883-3022	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-1733.